

Abstract

We describe here the design characterization of PSEC-4: a custom analog and digital integrated circuit designed in the IBM-8RF 0.13 µm process intended for fast (>10 GSa/s), low-power waveform digitizing. As part of the Large-Area Picosecond Photo-Detector (LAPPD) collaboration, this ASIC has been designed for the front-end transmission line readout of large area micro-channel plates (MCP), among other potential applications. With 6 channels, PSEC-4 has a buffer depth of 256 analog samples on each channel, a chip-parallel 1.5 GHz Wilkinson ADC, and a serial data readout that includes the capability for region-of-interest windowing to reduce

dead time. A switched-capacitor array architecture was implemented and sampling lock is possible with an on-chip delay locked loop (DLL) with a measured jitter of better than 15 ps. Chip performance results, including sampling rates up to 17 GSa/s, RMS noise less than 1 mV, and an analog bandwidth (ABW) of 1.6 GHz, are presented.

Principle of Operation



Channel Block Diagram

- 256-sample switched capacitor array architecture
- Parallel 1.5 GHz Wilkinson digitization
- Serial data readout (token)



Timing control #n-1, #n, #n+1

PSEC-4 die & Evaluation Board





DCFC-4 ACTC

PSEC-4 Results

	ACTUAL PERFORMANCE
Sampling Rate	2.5-15 GSa/s
# Channels	6 (or 2)
Sampling Depth	256 (or 768) points
Sampling Window	Depth*(Sampling Rate) ⁻¹
Input Noise	<1 mV RMS
Analog Bandwidth	1.5 GHz
ADC conversion	Up to 12 bit @ 1.5 GHz
Dynamic Range	0.1-1.1 V
Latency	2 μs (min) – 16 μs (max)
Internal Trigger	yes

Digitized Waveforms



Noise



Linearity

Sampling rate : 10 GSa/s

Sampling rate : 13.3 GSa/s



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